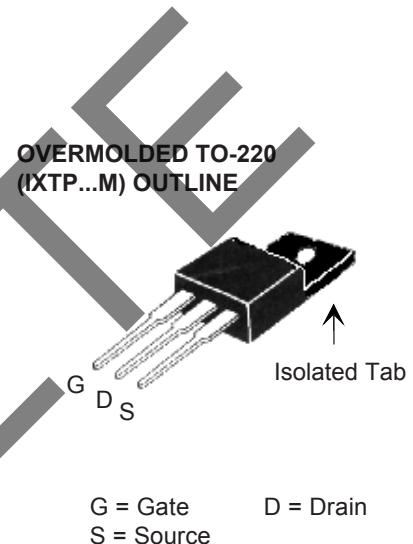
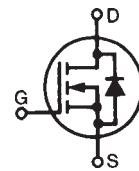


**PolarHV™ HiPerFET
Power MOSFET
(Electrically Isolated Tab)**

N-Channel Enhancement Mode
Avalanche Rated
Fast Intrinsic Diode

IXFP 8N50PM

V_{DSS}	=	500	V
I_{D25}	=	4.4	A
$R_{DS(on)}$	\leq	0.8	Ω
t_{rr}	\leq	200	ns



Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ C$ to $150^\circ C$	500		V
V_{DGR}	$T_J = 25^\circ C$ to $150^\circ C$; $R_{GS} = 1 M\Omega$	500		V
V_{GS}	Continuous	± 30		V
V_{GSM}	Transient	± 40		V
I_{D25}	$T_c = 25^\circ C$	4.4		A
I_{DM}	$T_c = 25^\circ C$, pulse width limited by T_{JM}	14		A
I_{AR}	$T_c = 25^\circ C$	8		A
E_{AR}	$T_c = 25^\circ C$	20		mJ
E_{AS}	$T_c = 25^\circ C$	300		mJ
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 A/\mu s$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ C$, $R_G = 18 \Omega$	10		V/ns
P_D	$T_c = 25^\circ C$	42		W
T_J		-55 ... +150		$^\circ C$
T_{JM}		150		$^\circ C$
T_{stg}		-55 ... +150		$^\circ C$
T_L	1.6 mm (0.062 in.) from case for 10 s	300		$^\circ C$
T_{SOLD}	Plastic body for 10 s	260		$^\circ C$
M_d	Mounting torque	1.13/10	Nm/lb.in.	
Weight		4		g

Symbol	Test Conditions ($T_J = 25^\circ C$ unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{DSS}	$V_{GS} = 0 V$, $I_D = 250 \mu A$	500		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 1 mA$	3.0		5.5 V
I_{GSS}	$V_{GS} = \pm 30 V_{DC}$, $V_{DS} = 0$		± 100	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 V$		5 500	μA
$R_{DS(on)}$	$V_{GS} = 10 V$, $I_D = 4 A$ Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2 \%$		0.8	Ω

Features

- ▀ Plastic overmolded tab for electrical isolation
- ▀ International standard package
- ▀ Unclamped Inductive Switching (UIS) rated
- ▀ Low package inductance
 - easy to drive and to protect
- ▀ Fast Intrinsic Diode

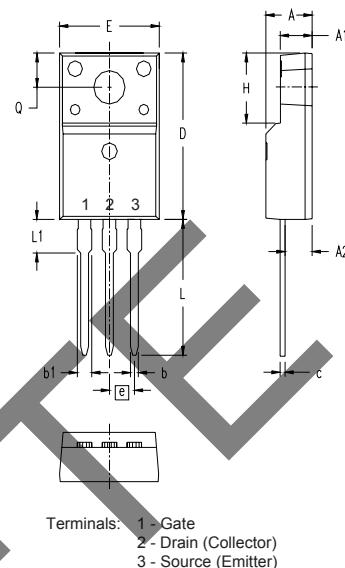
Advantages

- ▀ Easy to mount
- ▀ Space savings
- ▀ High power density

Symbol	Test Conditions	Characteristic Values			
		($T_J = 25^\circ C$ unless otherwise specified)	Min.	Typ.	Max.
g_{fs}	$V_{DS} = 10 V; I_D = 4 A$		5	8	S
C_{iss}		1050		pF	
C_{oss}		120		pF	
C_{rss}		12		pF	
$t_{d(on)}$		22		ns	
t_r		28		ns	
$t_{d(off)}$		65		ns	
t_f		23		ns	
$Q_{g(on)}$		20		nC	
Q_{gs}		7		nC	
Q_{gd}		7		nC	
R_{thJS}			3.0	$^\circ C/W$	

Source-Drain Diode

Symbol	Test Conditions	Characteristic Values			
		($T_J = 25^\circ C$, unless otherwise specified)	Min.	Typ.	Max.
I_s	$V_{GS} = 0 V$			8	A
I_{SM}	Repetitive			14	A
V_{SD}	$I_F = I_s, V_{GS} = 0 V,$ Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2\%$		1.5		V
t_{rr}			0.25		ns
Q_{RM}			2		μC
I_{RM}	$I_F = 8 A, V_{GS} = 0 V, V_R = 100 V$ $-di/dt = 100 A/\mu s$			200	A

ISOLATED TO-220 (IXTP...M)

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.177	.193	4.50	4.90
A1	.092	.108	2.34	2.74
A2	.101	.117	2.56	2.96
b	.028	.035	0.70	0.90
b1	.050	.058	1.27	1.47
c	.018	.024	0.45	0.60
D	.617	.633	15.67	16.07
E	.392	.408	9.96	10.36
e	.100	BSC	2.54	BSC
H	.255	.271	6.48	6.88
L	.499	.523	12.68	13.28
L1	.119	.135	3.03	3.43
ØP	.121	.129	3.08	3.28
Q	.126	.134	3.20	3.40

PRELIMINARY TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from data gathered during objective characterizations of preliminary engineering lots; but also may yet contain some information supplied during a pre-production design evaluation. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

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IXYS MOSFETs and IGBTs are covered by 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585 one or more of the following U.S. patents: 4,850,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343 6,710,405B2 6,759,692 4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505 6,710,463 6,771,478 B2